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FCH099N60E

July 2015

N-Channel SuperFET® II Easy-Drive MOSFET

600 V, 37 A, 99 mΩ

Features

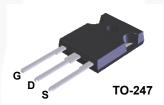
- 650 V @ T_J = 150°C
- Typ. $R_{DS(on)}$ = 87 m Ω
- Ultra Low Gate Charge (Typ. Q_g = 88nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 309 pF)
- · 100% Avalanche Tested
- · RoHS Compliant

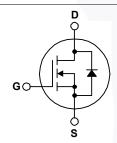
Applications

- Telecom / Sever Power Supplies
- · Industrial Power Supplies

Description

SuperFET® II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET easy-drive series offers slightly slower rise and fall times compared to the SuperFET II MOSFET series. Noted by the "E" part number suffix, this family helps manage EMI issues and allows for easier design implementation. For faster switching in applications where switching losses must be at an absolute minimum, please consider the SuperFET II MOSFET series.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol			FCH099N60E	Unit		
V _{DSS}	Drain to Source Voltage			600	V	
V _{GSS}	Cata ta Causaa Valtaria	- DC		±20	V	
	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	V	
	Drain Current	- Continuous (T _C = 25°C)	/	37		
ID	Drain Current	- Continuous (T _C = 100°C)		24	A	
I _{DM}	Drain Current	- Pulsed	(Note 1)	111	Α	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	809	mJ	
I _{AR}	Avalanche Current (Note 1)		6.8	Α		
E _{AR}	Repetitive Avalanche Energy		(Note 1)	3.57	mJ	
dv/dt	MOSFET dv/dt		100	1//		
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20	V/ns	
D	Davies Discination	$(T_C = 25^{\circ}C)$		357	W	
P_{D}	Power Dissipation - Derate Above 25°C		2.85	W/°C		
T _J , T _{STG}	Operating and Storage Temperat	ure Range		-55 to +150	οС	
TL	Maximum Lead Temperature for	Soldering, 1/8" from Case for 5	Seconds	300	οС	

Thermal Characteristics

Symbol	Parameter	FCH099N60E	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.35	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	- 0/00

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCH099N60E	FCH099N60E	TO-247	Tube	N/A	N/A	30 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charae	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 10 \text{ mA}, T_J = 25^{\circ}\text{C}$	600	-	-	V
		$V_{GS} = 0 \text{ V}, I_D = 10 \text{ mA}, T_J = 150^{\circ}\text{C}$	650	-	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 10 mA, Referenced to 25°C	-	0.7	-	V/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V	-	-	1	μА
IDSS		$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	2.1	-	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	-	3.5	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 18.5 \text{ A}$	-	87	99	mΩ
9 _{FS}	Forward Transconductance	$V_{DS} = 20 \text{ V}, I_{D} = 18.5 \text{ A}$	-	31.4	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 000 V V 0 V	-	2604	3465	pF
C _{oss}	Output Capacitance	$V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	-	75	100	pF
C _{rss}	Reverse Transfer Capacitance	1 111112	-\	13.9	20	pF
Coss(eff.)	Effective Output Capacitance	$V_{DS} = 0 \text{ V to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	- \	309	-	pF
$Q_{g(tot)}$	Total Gate Charge at 10V	V _{DS} = 380 V, I _D = 18.5 A,	- \	88	114	nC
Q_{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	12	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	38	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.6	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	24	58	ns
t _r	Turn-On Rise Time	$V_{DD} = 380 \text{ V}, I_D = 18.5 \text{ A},$		-	23	56	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_g = 4.7 Ω		-/	92	194	ns
t _f	Turn-Off Fall Time	4)	Note 4)	_	22	54	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current			-	37	Α
I _{SM}	Maximum Pulsed Drain to Source Diode F	Maximum Pulsed Drain to Source Diode Forward Current			111	Α
V_{SD}	Drain to Source Diode Forward Voltage	Drain to Source Diode Forward Voltage V _{GS} = 0 V, I _{SD} = 18.5 A		-	1.2	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 18.5 A,	-	387	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	7.3	-	μС

Notes:

- 1. Repetitive rating: pulse width limited by maximum junction temperature.
- 2. I_{AS} = 6.8 A, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 3. I $_{SD} \leq$ 18.5 A, di/dt \leq 200 A/µs, V $_{DD} \leq$ 380 V, Starting T $_{J}$ = 25°C
- 4. Essentially independent of operating temperature.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

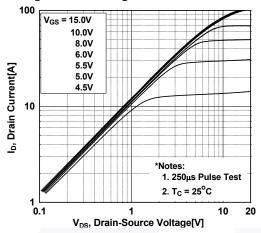


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

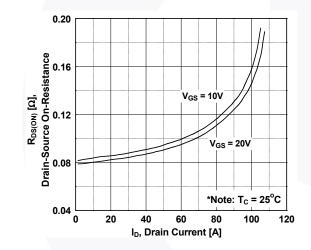


Figure 5. Capacitance Characteristics

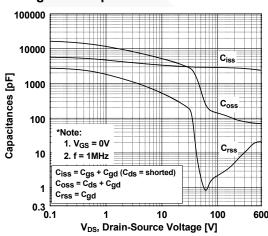


Figure 2. Transfer Characteristics

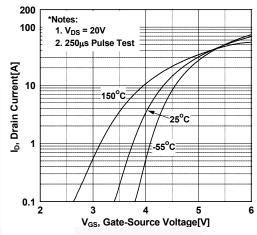


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

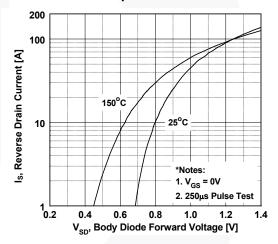
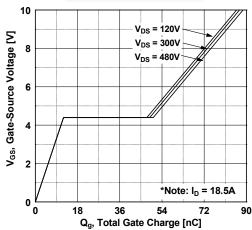


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

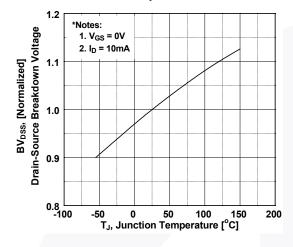


Figure 9. Maximum Safe Operating Area

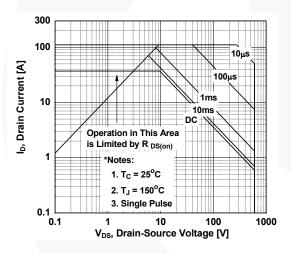


Figure 11. Eoss vs. Drain to Source Voltage

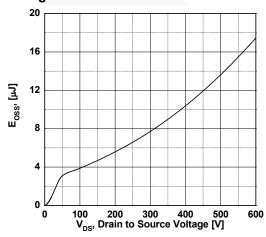


Figure 8. On-Resistance Variation vs. Temperature

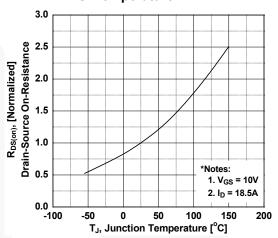
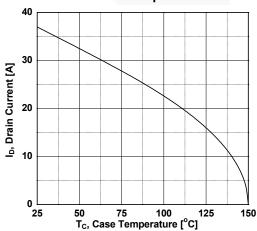


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve

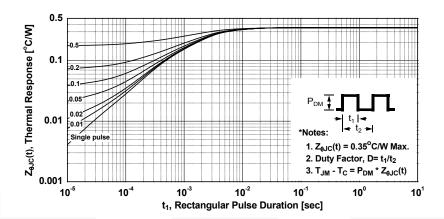


Figure 13. Gate Charge Test Circuit & Waveform

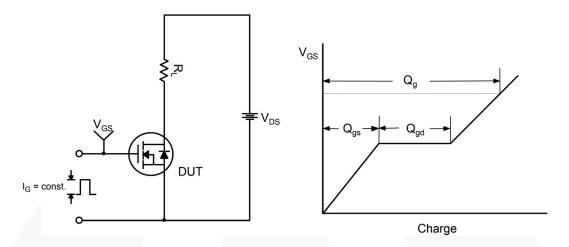


Figure 14. Resistive Switching Test Circuit & Waveforms

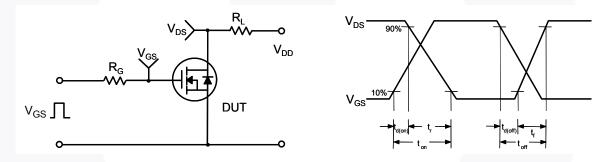
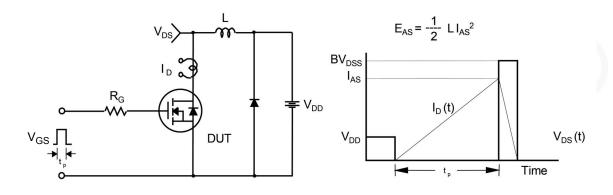


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms



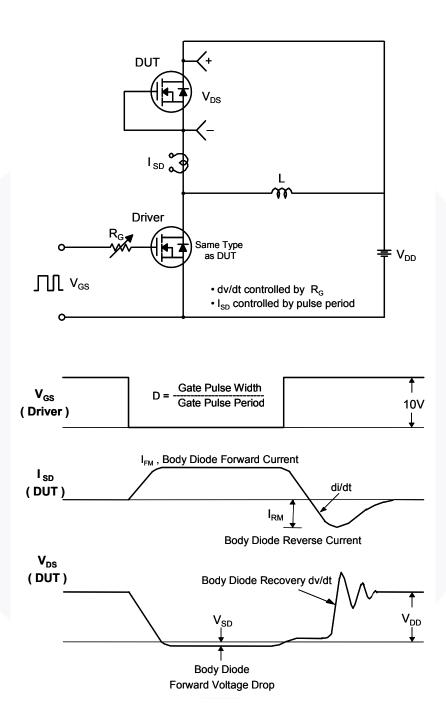
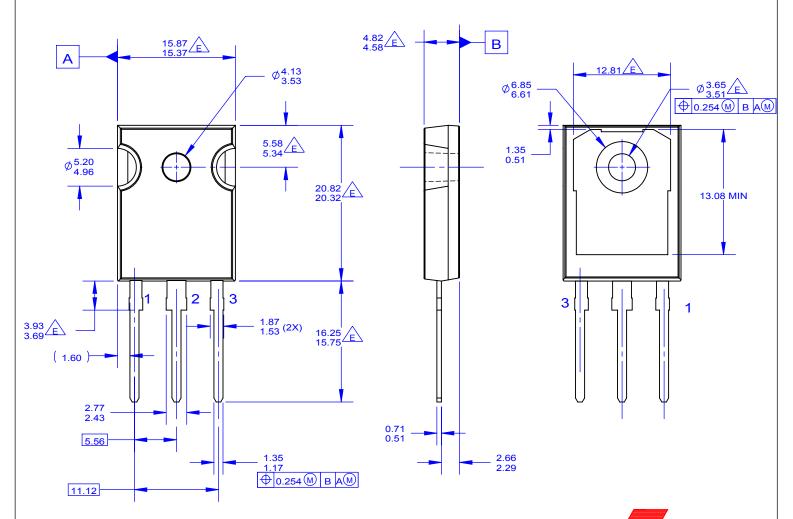


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms





NOTES: UNLESS OTHERWISE SPECIFIED.

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